

Lecture 2

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Empirical Risk Minimization and Complexity

Agenda

- Binary classification - Goal and Probabilistic setup
- The Principle of Empirical Risk Minimization (ERM)
- A first go - the finite case
- Concentration Bounds - McDiarmid's Inequality
- The Vapnik-Chervonenkis inequality
- Complexity (Combinatorial) - VC Dimension

Probabilistic setup for binary classification

- Random pair $= (X, Y) \sim P$ unknown
- X = observation vector in \mathcal{X} (ex: \mathbb{R}^d with $d \gg 1$)
- Y = binary label in $\mathcal{Y} = \{-1, +1\}$
- **Our goal:** guess the *output* Y from the *input* observation X
- **Classifier:** $C : x \in \mathcal{X} \mapsto C(x) \in \{-1, 1\}$ in a **class** \mathcal{G}
- Risk functional (unknown!) = **Expected prediction error**

$$L(C) = \mathbb{E}[\mathbb{I}\{Y \neq C(X)\}]$$

to minimize over $C \in \mathcal{G}$

- \mathcal{G} is in 1-to-1 correspondence with the class of sets $\{\{x \in \mathcal{X} : C(x) = +1\} : C \in \mathcal{G}\}$

Theoretical Risk Minimization

- Let $\eta(x) = \mathbb{P}(Y = +1|X = x)$ **regression function**
- Let $p = \mathbb{P}(Y = +1)$
- Compute $C^* = \arg \min_{C \in \mathcal{G}} L(C)$
- Calculations yields the **Naive Bayes Classifier**

$$C^*(x) = 2 \cdot \mathbb{I}\{\eta(x) > 1/2\} - 1, \quad x \in \mathcal{X}$$

\Rightarrow affects the likeliest label given the observation $X = x$

- Minimum theoretical risk: $L^* = L(C^*) = 1/2 - \mathbb{E}[|\eta(X) - 1/2|]$
- How close $\eta(X)$ is to $1/2$ governs the difficulty of the problem!

Theoretical Risk Minimization

- Theoretical **excess of risk**:

$$L(C) - L^* = \mathbb{E}[|\eta(X) - 1/2| \mathbb{I}\{X \in G^* \Delta G_C\}]$$

where G^* , G_C denote the subsets of the input space \mathcal{X}

$$G^* = \{\eta(X) > 1/2\}$$

$$G_C = \{C(X) = +1\}$$

and $A \Delta B = (A \cap \bar{B}) \cup (\bar{A} \cap B)$ the *symmetric difference*.

- Insights: when a little of X 's mass is concentrated around the **margin** $\{\eta(x) = 1/2\}$, the problem gets simpler.

Empirical Risk Minimization (ERM)

- Data = $D_n = \{(X_1, Y_1), \dots, (X_n, Y_n)\}$
- Classifier candidate: $C : \mathcal{X} \rightarrow \{-1, 1\}$ in a class \mathcal{G}
- Empirical risk functional = Training (misclassification) error

$$L_n(C) = \frac{1}{n} \sum_{i=1}^n \mathbb{I}\{Y_i \neq C(X_i)\}$$

to minimize over $C \in \mathcal{G}$.

- Solution "**empirical risk minimizer**": $\hat{C}_n = \arg \min_{C \in \mathcal{G}} L_n(C)$
- OK for the training data, now for **future data** (X, Y) ?

Empirical Risk Minimization (ERM) - Heuristics

- $L_n(C)$ must be close to $L(C)$, uniformly over $C \in \mathcal{G}$
- For any fixed C , this is true (SLLN, CLT, Berry-Esseen, *etc.*)
- This should remain true, provided that \mathcal{G} is **not too complex**, whatever (X, Y) 's distribution

Investigating the properties of the ER Minimizer

- Don't forget that \hat{C}_n is **random** (depending on the data D_n)
- Let $(X, Y) \sim P$ be a **new random pair**, independent from D_n
Will \hat{C}_n performs well as a classifier for this novel pair?

$$\Rightarrow \text{compute } L(\hat{C}_n) = \mathbb{P}(Y \neq \hat{C}_n(X) \mid D_n)$$

- $L(\hat{C}_n)$ is a **random variable**! It depends on the data D_n .
- **Deviation** between the r.v. $L(\hat{C}_n)$ and the min. error L^* (cst)

$$\Rightarrow \text{Study the excess of risk } 0 \leq \mathcal{E}(C) = L(\hat{C}_n) - L^*$$

- Learning Theory: compute explicit **confidence bounds**, $\forall \epsilon > 0$

$$\mathbb{P}_{D_n}(L(\hat{C}_n) - L^* \geq \epsilon) \leq ?$$

Learning Bounds

- Consider $C_0 = \arg \min_{C \in \mathcal{G}} L(C)$ (theoret. minimizer over \mathcal{G})
- Check the "**bias-variance**" decomposition

$$L(\hat{C}_n) - L^* \leq 2 \sup_{C \in \mathcal{G}} |L(C) - \hat{L}_n(C)| + L(C_0) - L^*$$

as \mathcal{G} "increases" ↗ ↘

- The second term depends on the model \mathcal{G} solely (bias)
- The 1st term (estimation) involves **concentration** of

$$Z = \{L(C) - \hat{L}_n(C)\}_{C \in \mathcal{G}}$$

⇒ theory of **empirical processes**

Empirical processes - Basics

- Let X_1, \dots, X_n be i.i.d. r.v.'s drawn as P
- Let $P_n = n^{-1} \sum_{i=1}^n \delta_{X_i}$ the empirical df
- Let \mathcal{F} be a class of functions $f : \mathbb{R} \rightarrow \mathbb{R}$
- **Empirical process** $\{P_n f\}_{f \in \mathcal{F}}$: $P_n f = n^{-1} \sum_{i=1}^n f(X_i)$, $f \in \mathcal{F}$
- Investigate which conditions on \mathcal{F} allow to **control**

$$\|Z\| = \sup_{f \in \mathcal{F}} |P_n f - P f|$$

- Ex.: recall **Donsker's theorem**, $\mathcal{F} = \{\mathbb{I}\{\cdot \leq x\}, x \in \mathbb{R}\}$

$$\sqrt{n} \sup_{x \in \mathbb{R}} |n^{-1} \sum_{i \leq n} \mathbb{I}\{X_i \leq x\} - P([-\infty, x])| \Rightarrow \sup_{t \in [0,1]} |B(t)|$$

Basics inequalities

- Finite class: $\text{Card}(\mathcal{F}) = N$.

"Union's bound" combined with **Chernoff's method**

$$\mathbb{P}\left(\sup_{f \in \mathcal{F}} |P_n f - P f| \geq \epsilon\right) \leq 2N \cdot e^{-2n\epsilon^2}$$

if $\forall f \in \mathcal{F} : 0 \leq f \leq 1$

- Cumulative distribution functions: **Dvoretzky-Kiefer-Wolfowitz**

$$\mathbb{P}\left(\sqrt{n} \sup_{x \in \mathbb{R}} \left| \frac{1}{n} \sum_{i \leq n} \mathbb{I}\{X_i \leq x\} - P([-\infty, x]) \right| \geq \epsilon\right) \leq 2e^{-2\epsilon^2}$$

- McDarmid (1989)

The finite situation

- **Hoeffding inequality** : X_1, \dots, X_n independent r.v.'s such that $-\infty < a_i \leq X_i \leq b_i < +\infty$ almost-surely. Let $S_n = \sum_{i \leq n} X_i$. Then, for any $\epsilon > 0$,

$$\mathbb{P}\{S_n - \mathbb{E}[S_n]\} \leq \exp \left\{ -\frac{2\epsilon^2}{\sum_{i=1}^n (b_i - a_i)^2} \right\}$$

- **Application to the ERM paradigm**: if $\#\mathcal{G} = N$, then: $\forall \epsilon > 0$,

$$\mathbb{P}\left\{\sup_{C \in \mathcal{G}} |\hat{L}_n(C) - L(C)| \geq \epsilon\right\} \leq 2Ne^{-2n\epsilon^2}$$

- Bound the expected maximal deviation

$$\mathbb{E}\left[\sup_{C \in \mathcal{G}} |\hat{L}_n(C) - L(C)|\right]$$

by integrating the bound: if $Z \geq 0$ a.s., $\mathbb{E}[Z] = \int_{t>0} \mathbb{P}\{Z \geq t\} dt$

The finite situation

- **Lemma:** Let Z_1, \dots, Z_n be r.v.'s such that: $\forall s > 0$, $\mathbb{E}[\exp sY_i] \leq \exp s^2\sigma^2/2$. Then

$$\mathbb{E}[\max_{1 \leq i \leq n} Z_i] \leq \sigma \sqrt{2 \log n}$$

- **Application:**

$$\mathbb{E}[\sup_{C \in \mathcal{G}} |\hat{L}_n(C) - L(C)|] \leq \sqrt{\frac{\log(2N)}{2n}}$$

McDarmid's inequality - Bounded differences

- $g : A^n \rightarrow \mathbb{R}$ such that: $\forall i \in \{1, \dots, n\}, \forall x \in A^n, \forall x'_i \in A,$

$$|g(x_1, \dots, x_{i-1}, x_i, x_{i+1}, \dots, x_n) - g(x_1, \dots, x_{i-1}, x'_i, x_{i+1}, \dots, x_n)| \leq c_i$$

- If X_1, \dots, X_n are independent and g has bounded differences, then:
 $\forall t > 0,$

$$\mathbb{P}\{g(X_1, \dots, X_n) - \mathbb{E}[g(X_1, \dots, X_n)] > t\} \leq e^{-\frac{2t^2}{\sum_{i=1}^n c_i^2}}$$

- **Application:** Whatever the class \mathcal{G} , we have:

$$\mathbb{P}\left\{\left|\sup_{C \in \mathcal{G}} |\hat{L}_n(C) - L(C)| - \mathbb{E}\left[\sup_{C \in \mathcal{G}} |\hat{L}_n(C) - L(C)|\right]\right| > \epsilon\right\} \leq 2e^{-2n\epsilon^2}$$

Measuring Complexity - Combinatorial Approach

- Vapnik - Chervonenkis: **VC dimension** of a class \mathcal{A} of subsets $A \subset \mathbb{R}^d$
- Let $x_1^n = (x_1, \dots, x_n)$ be n points in \mathbb{R}^d . Define

- ▶ **Trace:**

$$Tr(\mathcal{A}, x_1^n) = \{A \cap x_1^n; A \in \mathcal{A}\}$$

- ▶ **Shattering coefficient:**

$$S_{\mathcal{A}}(n) = \max_{x_1^n} \text{Card} Tr(\mathcal{A}, x_1^n)$$

- ▶ Ex: half-lines of \mathbb{R} : $S_{\mathcal{A}}(n) = n + 1$
- Other approaches: entropy metric, Rademacher chaos, etc.

Vapnik-Chervonenkis inequality

- \mathcal{A} class of borelian subsets $A \subset \mathbb{R}^d$, μ probability measure on \mathbb{R}^d
- $X_i \stackrel{i.i.d.}{\sim} \mu(dx)$, empirical measure $\hat{\mu}_n = (1/n) \sum_{i \leq n} \delta_{X_i}$

- **Result:**

$$\mathbb{E} \left[\sup_{A \in \mathcal{A}} |\hat{\mu}_n(A) - \mu(A)| \right] \leq 2 \sqrt{\frac{\log(2S_{\mathcal{A}}(n))}{n}}$$

- **Proof:** Ghost sample $X'_i \stackrel{i.i.d.}{\sim} \mu(dx)$ independent from X_1, \dots, X_n
 $\hat{\mu}'_n = (1/n) \sum_{i \leq n} \delta_{X'_i}$

$$\begin{aligned} \mathbb{E} \left[\sup_{A \in \mathcal{A}} |\hat{\mu}_n(A) - \mu(A)| \right] &= \mathbb{E} \left[\sup_{A \in \mathcal{A}} |\mathbb{E}[\hat{\mu}_n(A) - \hat{\mu}'_n(A) \mid X'_1, \dots, X'_n]| \right] \\ &\leq \mathbb{E} \left[\sup_{A \in \mathcal{A}} \mathbb{E}[|\hat{\mu}_n(A) - \hat{\mu}'_n(A)| \mid X'_1, \dots, X'_n] \right] \\ &\leq \mathbb{E} \left[\sup_{A \in \mathcal{A}} |\hat{\mu}_n(A) - \hat{\mu}'_n(A)| \right] \text{ symmetrization} \end{aligned}$$

Vapnik-Chervonenkis inequality

randomization: consider a Rademacher chaos $\sigma_1, \dots, \sigma_n$, i.i.d. and independent from the (X_i, X'_i) 's, $\mathbb{P}\{\sigma_i = +1\} = \mathbb{P}\{\sigma_i = -1\} = 1/2$

$$\mathbb{E} \left[\sup_{A \in \mathcal{A}} |\hat{\mu}_n(A) - \mu(A)| \right] \leq \frac{1}{n} \times$$

$$\mathbb{E} \left[\mathbb{E} \left[\sup_{A \in \mathcal{A}} \left| \sum_{i=1}^n \sigma_i (\mathbb{I}\{X_i \in A\} - \mathbb{I}\{X'_i \in A\}) \right| \mid X_1, \dots, X_n, X'_1, \dots, X'_n \right] \right]$$

Observe that, for fixed $(X_1, X'_1), \dots, (X_n, X'_n)$, $\sup_{\mathcal{A}} = \max_{\hat{\mathcal{A}}}$ with $\#\hat{\mathcal{A}} \leq S_{\mathcal{A}}(2n)$ and

$$\mathbb{E} \left[\max_{\hat{\mathcal{A}}} \left| \sum_{i=1}^n \sigma_i (\mathbb{I}\{x_i \in A\} - \mathbb{I}\{x'_i \in A\}) \right| \right] \leq \sqrt{2n \log(2S_{\mathcal{A}}(2n))}$$

Notice finally that $S_{\mathcal{A}}(2n) \leq S_{\mathcal{A}}(n)^2$

Vapnik-Chervonenkis dimension

- $\dim_{VC} \mathcal{A} = \max\{n \geq 1 : S_{\mathcal{A}}(n) = 2^n\}$
- **Application to ERM:** if $\dim_{VC} \mathcal{G} = V_{\mathcal{G}}$,

$$\begin{aligned} \mathbb{E}[L(\hat{C}_n) - \inf_{C \in \mathcal{G}} L(C)] &\leq 4 \sqrt{\frac{\log(2S_{\mathcal{G}}(n))}{n}} \\ &\leq 4 \sqrt{\frac{V_{\mathcal{G}} \log(n+1) + \log 2}{n}} \end{aligned}$$

Shatter coefficients - Basic properties

- $S_{\mathcal{A}}(n+m) \leq S_{\mathcal{A}}(n) \times S_{\mathcal{A}}(m)$
- If $\mathcal{C} = \mathcal{A} \cup \mathcal{B}$, then $S_{\mathcal{C}}(n) \leq S_{\mathcal{A}}(n) + S_{\mathcal{B}}(n)$
- If $\mathcal{B} = \{A^c : A \in \mathcal{A}\}$, then $S_{\mathcal{A}}(n) = S_{\mathcal{B}}(n)$
- If $\mathcal{C} = \{A \cap B : A \in \mathcal{A}, B \in \mathcal{B}\}$, then $S_{\mathcal{C}}(n) \leq S_{\mathcal{A}}(n) \times S_{\mathcal{B}}(n)$
- If $\mathcal{C} = \{A \times B : A \in \mathcal{A}, B \in \mathcal{B}\}$, then $S_{\mathcal{C}}(n) \leq S_{\mathcal{A}}(n) \times S_{\mathcal{B}}(n)$
- **Sauer lemma** If $\dim_{VC} \mathcal{A} = V < +\infty$, then

$$S_{\mathcal{A}}(n) \leq \sum_{i=0}^V \binom{n}{i}$$

- If $\dim_{VC} \mathcal{A} = V < +\infty$, then, $\forall n$, we have $S_{\mathcal{A}}(n) \leq (n+1)^V$
- If $\dim_{VC} \mathcal{A} = V < +\infty$, then, $\forall n \geq V$, we have $S_{\mathcal{A}}(n) \leq (ne/V)^V$

Examples

- If \mathcal{A} is the class of all rectangles in \mathbb{R}^d , then $V = 2d$
- Let \mathcal{G} be an m -dimensional vector space of functions $g : \mathbb{R}^d \rightarrow \mathbb{R}$.
The class

$$\mathcal{A} = \{\{x : g(x) = 0\} : g \in \mathcal{G}\}$$

has VC dimension $V \leq m$

- **Consequences:**

- ▶ the class of all linear halfspaces
 $\{\{x \in \mathbb{R}^d : A^t x \geq b\} : A \in \mathbb{R}^d, b \in \mathbb{R}\}$ has VC dimension $\leq d + 1$
- ▶ the class of all closed balls $\{\{x \in \mathbb{R}^d : \|x - c\| \geq b\} : c \in \mathbb{R}^d, b \in \mathbb{R}\}$
has VC dimension $\leq d + 2$
- ▶ the class of all ellipsoids
 $\{\{x \in \mathbb{R}^d : x^t \Gamma^{-1} x \leq 1\} : \Gamma \text{ symmetric positive definite}\}$ has VC
dimension $\leq d(d+1)/2 + 1$

Application:

- VC theory provides **statistical guarantees** (generalization ability) for application of the ERM principle based on
 - ▶ binary decision trees with perpendicular/diagonal splits
 - ▶ general partitioning techniques with hypercubes
 - ▶ linear separators
 - ▶ *etc.*
- VC theory is **useless** for
 - ▶ nonlinear SVM
 - ▶ boosting
 - ▶ random forest
- but VC theory will return ... for the purpose of **model selection** (structural risk minimization)